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| Notice of References Cited | Application/Control No. 10/552,750 | Applicant(s)/Patent Under Reexamination LAUER ET AL. | |
| | Examiner Andre J. Allen | Art Unit 2855 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-6,446,023 | 09-2002 | Ernst, Gerhard | 702/138 |
| * | B | US-6,946,954 | 09-2005 | Piech et al. | 340/444 |
| * | C | US-2005/0000278 | 01-2005 | Haralampu et al. | 073/146 |
| * | D | US-2005/0258949 | 11-2005 | Iwazumi, Keichi | 340/442 |
| * | E | US-2006/0273890 | 12-2006 | Kontogeorgakis et al. | 340/445 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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